

General Description

The MAX5186 contains two 8-bit, simultaneous-update, current-output digital-to-analog converters (DACs) designed for superior performance in communications systems requiring analog signal reconstruction with low distortion and low-power operation. The MAX5189 provides equal specifications, with on-chip precision resistors for voltage output operation. The MAX5186/ MAX5189 are designed for a 10pVs glitch operation to minimize unwanted spurious signal components at the output. An on-board +1.2V bandgap circuit provides a well-regulated, low-noise reference that can be disabled for external reference operation.

The MAX5186/MAX5189 are designed to provide a high level of signal integrity for the least amount of power dissipation. Both DACs operate from a single supply voltage of +2.7V to +3.3V. Additionally, these DACs have three modes of operation: normal, low-power standby, and complete shutdown, which provides the lowest possible power dissipation with a 1µA (max) shutdown current. A fast wake-up time (0.5µs) from standby mode to full DAC operation allows power conservation by activating the DACs only when required.

The MAX5186/MAX5189 are packaged in a 28-pin QSOP and are specified for the extended (-40°C to +85°C) temperature range. For higher resolution, dual 10-bit versions, refer to the MAX5180/MAX5183 data sheet.

Applications

Signal Reconstruction of I and Q **Transmit Signals** Digital Signal Processing Arbitrary Waveform Generation (AWG) **Imaging Applications**

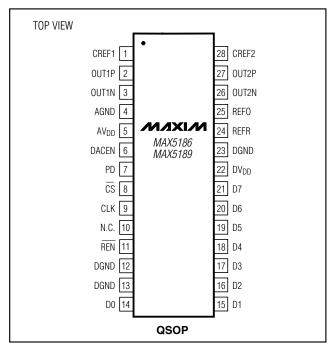
Features

- ♦ +2.7V to +3.3V Single-Supply Operation
- ♦ Wide Spurious-Free Dynamic Range: 70dB at four = 2.2MHz
- **♦ Fully Differential Outputs for Each DAC**
- ♦ ±0.5% FSR Gain Mismatch
- ♦ ±0.15° Phase Mismatch
- ♦ Low-Current Standby or Full Shutdown Modes
- ♦ Internal +1.2V, Low-Noise Bandgap Reference
- ♦ Small 28-Pin QSOP Package

Ordering Information

PART	TEMP. RANGE	PIN-PACKAGE		
MAX5186BEEI	-40°C to +85°C	28 QSOP		
MAX5189BEEI	-40°C to +85°C	28 QSOP		

Pin Configuration



MIXIM

Maxim Integrated Products 1

ABSOLUTE MAXIMUM RATINGS

AV _{DD} , DV _{DD} to AGND, DGND Digital Input to DGND	
OUT1P. OUT1N. OUT2P. OUT2N. CREF1.	0.5V tO +0V
CREF2 to AGND	0.21/+061/
VREF to AGND	
AGND to DGND	0.3V to +0.3V
AV _{DD} to DV _{DD}	±3.3V
Maximum Current into Any Pin	50mA

Continuous Power Dissipation (T _A = +70°C))
28-Pin QSOP (derate 9.00mW/°C above -	+70°C) 725mW
Operating Temperature Ranges	
MAX518_BEEI	40°C to +85°C
Storage Temperature Range	
Lead Temperature (soldering, 10sec)	+300°C

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

ELECTRICAL CHARACTERISTICS

 $(AV_{DD} = DV_{DD} = +3V \pm 10\%, AGND = DGND = 0, f_{CLK} = 40MHz, I_{FS} = 1mA, 400\Omega$ differential output, $C_L = 5pF, T_A = T_{MIN}$ to T_{MAX} , unless otherwise noted. Typical values are at $T_A = +25^{\circ}C$.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
STATIC PERFORMANCE			l			1
Resolution N			8			Bits
Integral Nonlinearity	INL		-1	±0.25	+1	LSB
Differential Nonlinearity	DNL	Guaranteed monotonic	-1	±0.25	+1	LSB
Zero-Scale Error		MAX5186	-1		+1 LSB	
Zero-Scale Error		MAX5189	-4		+4	LOD
Full-Scale Error		(Note 1)	-20	±4	+20	LSB
DYNAMIC PERFORMANCE	•		•			
Output Settling Time		To ±0.5LSB error band		25		ns
Glitch Impulse				10		pVs
Spurious-Free Dynamic Range	SFDR	f _{OUT} = 550kHz, f _{CLK} = 40MHz		72		- dBc
to Nyquist		f _{OUT} = 2.2MHz, f _{CLK} = 40MHz	57	70		ubc
Total Harmonic Distortion	THD	f _{OUT} = 550kHz, f _{CLK} = 40MHz		-70		dB
to Nyquist	טחו	f _{OUT} = 2.2MHz, f _{CLK} = 40MHz		-68	-63	1 46
Signal-to-Noise-Ratio to Nyquist	t SNR	f _{OUT} = 550kHz, f _{CLK} = 40MHz		52		dB
Signal-to-Noise-Hatio to Nyquist	SIVIT	f _{OUT} = 2.2MHz, f _{CLK} = 40MHz	46	52		T GB
DAC-to-DAC Output Isolation		f _{OUT} = 2.2MHz		-60		dB
Clock and Data Feedthrough		All 0s to all 1s		50		nVs
Output Noise				10		pA/√Hz
Gain Mismatch Between DAC Outputs		f _{OUT} = 2.2MHz		±0.5	±1	LSB
Phase Mismatch Between DAC Outputs		f _{OUT} = 2.2MHz		±0.15		degrees

ELECTRICAL CHARACTERISTICS (continued)

 $(AV_{DD} = DV_{DD} = +3V \pm 10\%, AGND = DGND = 0, f_{CLK} = 40MHz, I_{FS} = 1mA, 400\Omega$ differential output, $C_L = 5pF$, $T_A = T_{MIN}$ to T_{MAX} , unless otherwise noted. Typical values are at $T_A = +25$ °C.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
ANALOG OUTPUT						
Full-Scale Output Voltage	VFS			400		mV
Voltage Compliance of Output			-0.3		0.8	V
Output Leakage Current		DACEN = 0, MAX5186 only	-1		1	μΑ
Full-Scale Output Current	IFS	MAX5186 only	0.5	1	1.5	mA
DAC External Output Resistor Load	RL	MAX5186 only		400		Ω
REFERENCE	I.					
Output Voltage Range	V _{REF}		1.12	1.2	1.28	V
Output Voltage Temperature Drift	TCV _{REF}			50		ppm/°C
Reference Output Drive Capability	IREFOUT			10		μΑ
Reference Supply Rejection				0.5		mV/V
Current Gain (IFS / IREF)				8		mA/mA
POWER REQUIREMENTS	1					
Analog Power-Supply Voltage	AV _{DD}		2.7		3.3	V
Analog Supply Current	IAV _{DD}	PD = 0, DACEN = 1, digital inputs at 0 or DV _{DD}		2.7	5.0	mA
Digital Power-Supply Voltage	DV _{DD}		2.7		3.3	V
Digital Supply Current	IDV _{DD}	PD = 0, DACEN = 1, digital inputs at 0 or DV _{DD}		4.2	5.0	mA
Standby Current	ISTANDBY	PD = 0, DACEN = 0, digital inputs at 0 or DV _{DD}		1.0	1.5	mA
Shutdown Current	I _{SHDN}	PD = 1, DACEN = X, digital inputs at 0 or DV _{DD} (X = don't care)		0.5	1	μΑ
LOGIC INPUTS AND OUTPUTS	1					ı
Digital Input Voltage High	VIH		2			V
Digital Input Voltage Low	V _{IL}				0.8	V
Digital Input Current	I _{IN}	$V_{IN} = 0$ or DV_{DD}			±1	μΑ
Digital Input Capacitance	CIN			10		рF
TIMING CHARACTERISTICS						
DAC1 DATA to CLK Rise Setup Time	t _{DS1}		10			ns
DAC2 DATA to CLK Fall Setup Time	t _{DS2}		10			ns
DAC1 CLK Rise to DATA Hold Time	t _{DH1}		0			ns
DAC2 CLK Fall to DATA Hold Time	t _{DH2}		0			ns

ELECTRICAL CHARACTERISTICS (continued)

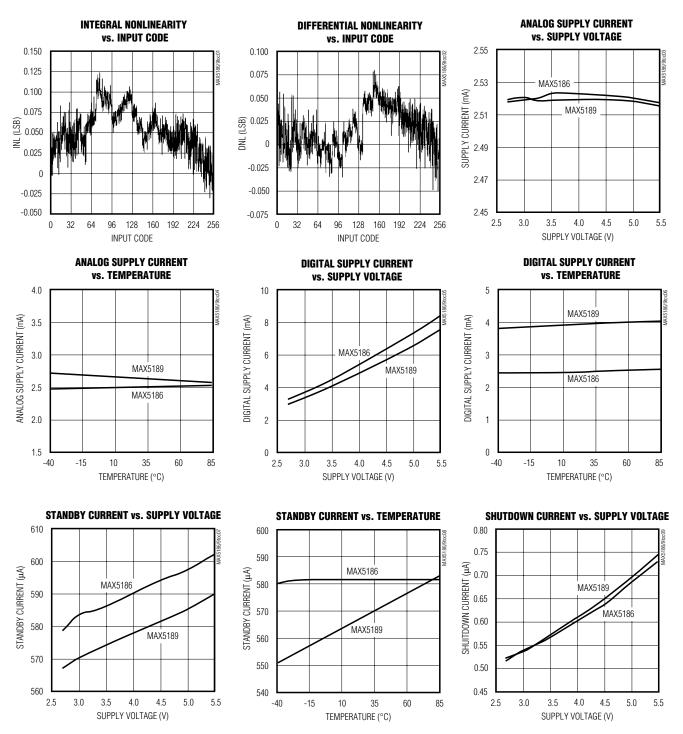
 $(AV_{DD} = DV_{DD} = +3V \pm 10\%, AGND = DGND = 0, f_{CLK} = 40MHz, I_{FS} = 1mA, 400\Omega$ differential output, $C_L = 5pF$, $T_A = T_{MIN}$ to T_{MAX} , unless otherwise noted. Typical values are at $T_A = +25$ °C.)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
CS Fall to CLK Rise Time				5		ns
CS Fall to CLK Fall Time				5		ns
DACEN Rise Time to Vout				0.5		μs
PD Fall Time to Vout				50		μs
Clock Period	tclk		25			ns
Clock High Time	tch		10			ns
Clock Low Time	tcL		10			ns

Note 1: Excludes reference and reference resistor (MAX5189) tolerance.

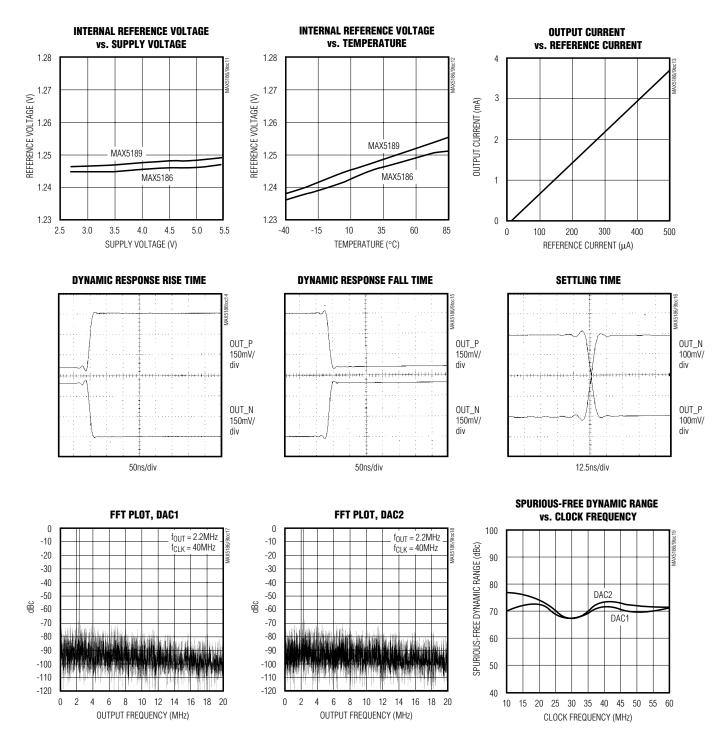
Typical Operating Characteristics

 $(AV_{DD} = DV_{DD} = +3V, AGND = DGND = 0, 400\Omega \text{ differential output, } I_{FS} = 1mA, C_L = 5pF, T_A = +25^{\circ}C, \text{ unless otherwise noted.})$



Typical Operating Characteristics (continued)

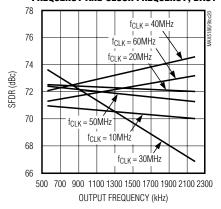
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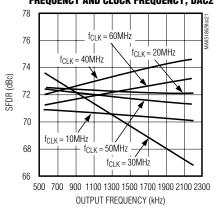
Typical Operating Characteristics (continued)

 $(AV_{DD} = DV_{DD} = +3V, AGND = DGND = 0, 400\Omega \text{ differential output, } I_{FS} = 1mA, C_L = 5pF, T_A = +25^{\circ}C, \text{ unless otherwise noted.})$

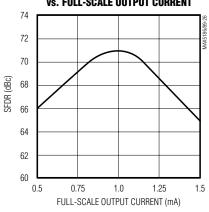
SPURIOUS-FREE DYNAMIC RANGE vs. OUTPUT FREQUENCY AND CLOCK FREQUENCY, DAC1



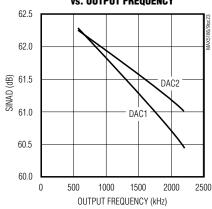
SPURIOUS-FREE DYNAMIC RANGE vs. OUTPUT FREQUENCY AND CLOCK FREQUENCY, DAC2



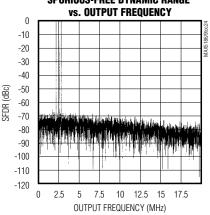
SPURIOUS-FREE DYNAMIC RANGE vs. Full-scale output current



SIGNAL-TO-NOISE + DISTORTION vs. OUTPUT FREQUENCY



MULTITONE Spurious-free Dynamic Range



Pin Description

PIN	NAME	FUNCTION
1	CREF1	Reference Bias Bypass, DAC1
2	OUT1P	Positive Analog Output, DAC1. Current output for MAX5186; voltage output for MAX5189.
3	OUT1N	Negative Analog Output, DAC1. Current output for MAX5186; voltage output for MAX5189.
4	AGND	Analog Ground
5	AV _{DD}	Analog Positive Supply, +2.7V to +3.3V
6	DACEN	DAC Enable, Digital Input 0: Enter DAC standby mode with PD = DGND. 1: Power-up DAC with PD = DGND. X: Enter shutdown mode with PD = DV _{DD} (X = don't care).
7	PD	Power-Down Select 0: Enter DAC standby mode (DACEN = DGND) or power-up DAC (DACEN = DV _{DD}). 1: Enter shutdown mode.
8	CS	Active-Low Chip Select
9	CLK	Clock input
10	N.C.	No Connect. Do not connect to this pin.
11	REN	Active-Low Reference Enable. Connect to DGND to activate on-chip +1.2V reference.
12	DGND	Digital Ground
13	DGND	Digital Ground
14	D0	Data Bit D0 (LSB)
15–20	D1-D6	Data Bits D1–D6
21	D7	Data Bit D7 (MSB)
22	DV _{DD}	Digital Supply, +2.7V to +3.3V
23	DGND	Digital Ground
24	REFR	Reference Input
25	REFO	Reference Output
26	OUT2N	Negative Analog Output, DAC2. Current output for MAX5186; voltage output for MAX5189.
27	OUT2P	Positive Analog Output, DAC2. Current output for MAX5186; voltage output for MAX5189.
28	CREF2	Reference Bias Bypass, DAC2

Detailed Description

The MAX5186/MAX5189 are dual, 8-bit digital-to-analog converters (DACs) capable of operating with clock speeds up to 40MHz. Each of these dual converters consists of separate input and DAC registers, followed by a current source array capable of generating up to 1.5mA full-scale output current (Figure 1). An integrated +1.2V voltage reference and control amplifier determine the data converters' full-scale output currents/voltages. Careful reference design ensures close gain matching and excellent drift characteristics. The MAX5189's voltage output operation features matched 400Ω on-chip resistors that convert the current array current into a voltage.

Internal Reference and Control Amplifier

The MAX5186/MAX5189 provide an integrated 50ppm/°C, +1.2V, low-noise bandgap reference that can be disabled and overridden by an external reference voltage. REFO serves either as an external reference input or an integrated reference output. If REN is connected to DGND, the internal reference is selected and REFO provides a +1.2V output. Due to its limited 10µA output drive capability, REFO must be buffered with an external amplifier if heavier loading is required.

The MAX5186/MAX5189 also employ a control amplifier designed to simultaneously regulate the full-scale output current (IFS) for both outputs of the devices. The output current is calculated as follows:

where IREF is the reference output current (IREF = VREFO/RSET) and IFS is the full-scale output current. RSET is the reference resistor that determines the amplifier's output current on the MAX5186 (Figure 2). This current is mirrored into the current source array where it is equally distributed between matched current segments and summed to valid output current readings for the DACs.

The MAX5189 converts each output current (DAC1 and DAC2) into an output voltage (VOUT1, VOUT2) with two internal, ground-referenced 400 Ω load resistors. Using the internal +1.2V reference voltage, the MAX5189's integrated reference output-current resistor (RSET = 9.6k Ω) sets IREF to 125 μ A and IFS to 1mA.

External Reference

To disable the MAX5186/MAX5189's internal reference, connect REN to DVDD. A temperature-stable, external reference may now be applied to drive the REFO pin to set the full-scale output (Figure 3). Choose a reference capable of supplying at least 150µA to drive the bias circuit that generates the cascode current for the current array. For improved accuracy and drift performance, choose a fixed output voltage reference such as the +1.2V, 25ppm/°C MAX6520 bandgap reference.

Standby Mode

To enter the lower power standby mode, connect digital inputs PD and DACEN to DGND. In standby, both the reference and the control amplifier are active with the current array inactive. To exit this condition, DACEN must be pulled high with PD held at DGND. Both the MAX5186/MAX5189 typically require 50µs to wake up and let both outputs and reference settle.

Shutdown Mode

For lowest power consumption, the MAX5186/MAX5189 provide a power-down mode in which the reference, control amplifier, and current array are inactive and the DACs' supply current is reduced to $1\mu A$. To enter this mode, connect PD to DVDD. To return to active mode, connect PD to DGND and DACEN to DVDD. About 50 μ s are required for the parts to leave shutdown mode and settle to their outputs' values prior to shutdown. Table 1 lists the power-down mode selection.

Timing Information

Both DAC cells residing in the MAX5186/MAX5189 write to their outputs simultaneously (Figure 4). The input latch of the first DAC (DAC1) is loaded after the clock signal transitions high. When the clock signal transitions low, the input latch of the second DAC (DAC2) is loaded. The contents of both input latches are simultaneously shifted to the DAC registers, and their outputs update at the rising edge of the next clock.

Outputs

The MAX5186 outputs are designed to supply full-scale output currents of 1mA into 400Ω loads in parallel with a capacitive load of 5pF. The MAX5189 features integrated 400Ω resistors that restore the array currents to proportional, differential voltages of 400mV. These differential output voltages can then be used to drive a balun transformer or a low-distortion, high-speed operational amplifier to convert the differential voltage into a single-ended voltage.

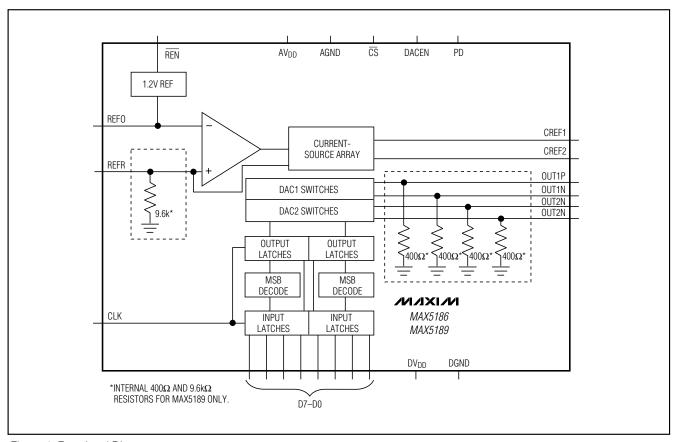


Figure 1. Functional Diagram

Applications Information

Static and Dynamic Performance Definitions

Integral Nonlinearity

Integral nonlinearity (INL) (Figure 5a) is the deviation of the values on an actual transfer function from either a best-straight-line fit (closest approximation to the actual transfer curve) or a line drawn between the endpoints of the transfer function once offset and gain errors have been nullified. For a DAC, the deviations are measured every single step.

Differential Nonlinearity

Differential nonlinearity (DNL) (Figure 5b) is the difference between an actual step height and the ideal value of 1LSB. A DNL error specification of less than 1LSB guarantees no missing codes and a monotonic transfer function.

Offset Error

Offset error (Figure 5c) is the difference between the ideal and the actual offset point. For a DAC, the offset point is the step value when the digital input is zero. This error affects all codes by the same amount and can usually be compensated by trimming.

Gain Error

Gain error (Figure 5d) is the difference between the ideal and the actual full-scale output voltage on the transfer curve after nullifying the offset error. This error alters the slope of the transfer function and corresponds to the same percentage error in each step.

Settling Time

Settling time is the amount of time required from the start of a transition until the DAC output settles its new output value to within the converter's specified accuracy.

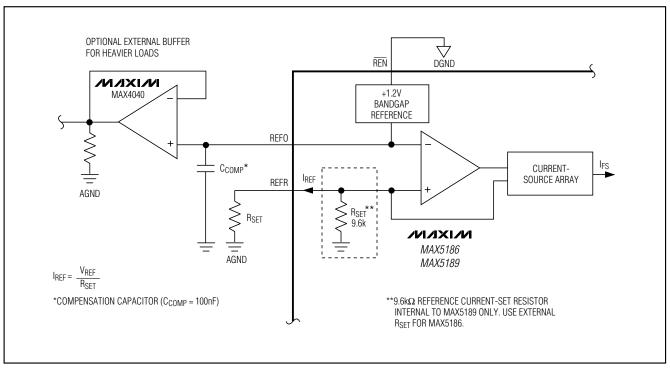


Figure 2. Setting IFS with the Internal +1.2V Reference and the Control Amplifier

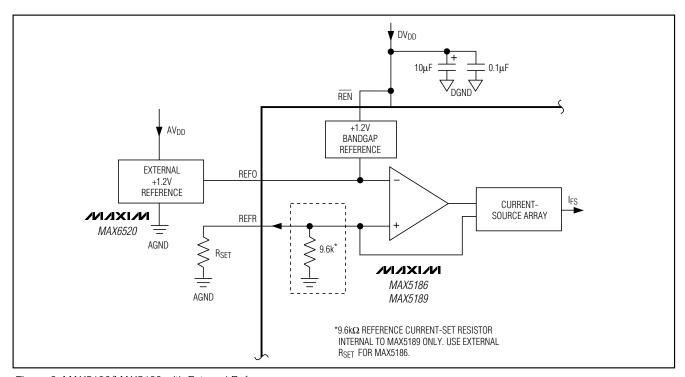


Figure 3. MAX5186/MAX5189 with External Reference

Table 1. Power-Down Mode Selection

PD (POWER-DOWN SELECT)	DACEN (DAC ENABLE)	POWER-DOWN MODE	OUTPUT STATE		
0	0 Standby	O Ctandby	Ctandby	MAX5186	High-Z
O		Standby	MAX5189	AGND	
0	1	Wake-Up	Last state prior to standby mode		
1	Х	X Shutdown	MAX5186	High-Z	
			MAX5189	AGND	

X = Don't care

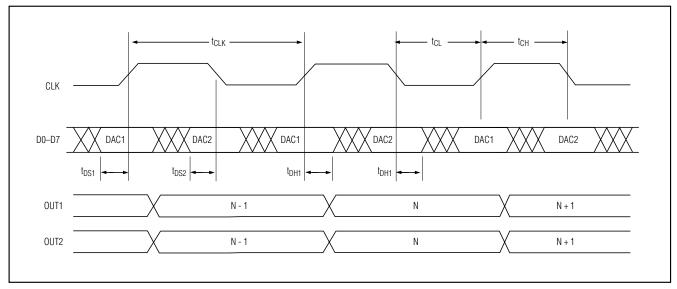


Figure 4. Timing Diagram

Digital Feedthrough

Digital feedthrough is the noise generated on a DAC's output when any digital input transitions. Proper board layout and grounding will significantly reduce this noise, but there will always be some feedthrough caused by the DAC itself.

Total Harmonic Distortion

Total harmonic distortion (THD) is the ratio of the RMS sum of the input signal's first five harmonics to the fundamental itself. This is expressed as:

THD =
$$20 \cdot \log \left(\frac{\sqrt{(V_2^2 + V_3^2 + V_4^2 + V_5^2)}}{V_1} \right)$$

where V_1 is the fundamental amplitude, and V_2 through V_5 are the amplitudes of the 2nd- through 5th-order harmonics.

Spurious-Free Dynamic Range

Spurious-free dynamic range (SFDR) is the ratio of RMS amplitude of the fundamental (maximum signal component) to the RMS value of the next-largest distortion component.

Differential to Single-Ended Conversion

The MAX4108 low-distortion, high-input bandwidth amplifier may be used to generate a voltage from the array current output of the MAX5186. The differential voltage across OUT1P (or OUT2P) and OUT1N (or OUT2N) is converted into a single-ended voltage by designing an appropriate operational amplifier configuration (Figure 6).

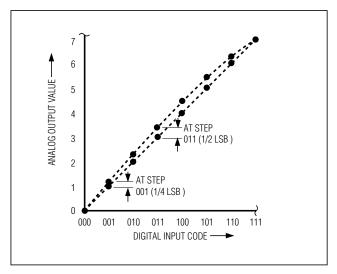


Figure 5a. Integral Nonlinearity

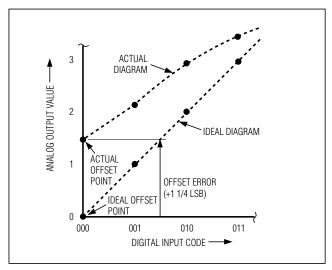


Figure 5c. Offset Error

I/Q Reconstruction in a QAM Application

The MAX5186/MAX5189's low distortion supports analog reconstruction of in-phase (I) and quadrature (Q) carrier components typically used in quadrature amplitude modulation (QAM) architectures where I and Q data are interleaved on a common data bus. A QAM signal is both amplitude and phase modulated, created by summing two independently modulated carriers of identical frequency but different phase (90° phase difference).

In a typical QAM application (Figure 7), the modulation occurs in the digital domain and the MAX5186/

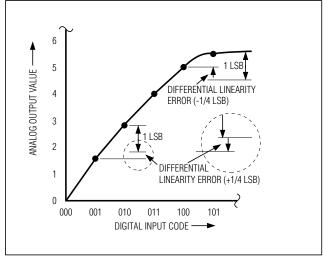


Figure 5b. Differential Nonlinearity

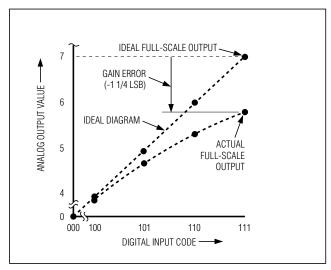


Figure 5d. Gain Error

MAX5189's dual DACs may be used to reconstruct the analog I and Q components.

The I/Q reconstruction system is completed by a quadrature modulator that combines the reconstructed I and Q components with in-phase and quadrature carrier frequencies and then sums both outputs to provide the QAM signal.

Grounding and Power-Supply Decoupling

Grounding and power-supply decoupling strongly influence the MAX5186/MAX5189's performance. Unwanted digital crosstalk may couple through the input, refer-

ence, power-supply, and ground connections, which may affect dynamic specifications like signal-to-noise ratio or SFDR. In addition, electromagnetic interference (EMI) can either couple into or be generated by the MAX5186/MAX5189. Therefore, grounding and power-supply decoupling guidelines for high-speed, high-frequency applications should be closely followed.

First, a multilayer printed circuit (PC) board with separate ground and power-supply planes is recommended. High-speed signals should be run on controlled impedance lines directly above the ground plane. Since the MAX5186/MAX5189 have separate analog and digital ground buses (AGND and DGND, respectively), the PC board should also have separate analog and digital ground sections with only one point con-

necting the two. Digital signals should run above the digital ground plane, and analog signals should run above the analog ground plane. Digital signals should be kept far away from the sensitive analog reference and clock input.

Both devices have two power-supply inputs: analog V_{DD} (AV_{DD}) and digital V_{DD} (DV_{DD}). Each AV_{DD} input should be decoupled with parallel 10µF and 0.1µF ceramic-chip capacitors. These capacitors should be as close to the pin as possible, and their opposite ends should be as close to the ground plane as possible. The DV_{DD} pins should also have separate 10µF and 0.1µF capacitors adjacent to their respective pins. Try to minimize analog load capacitance for proper operation. For best performance, it is recommended to

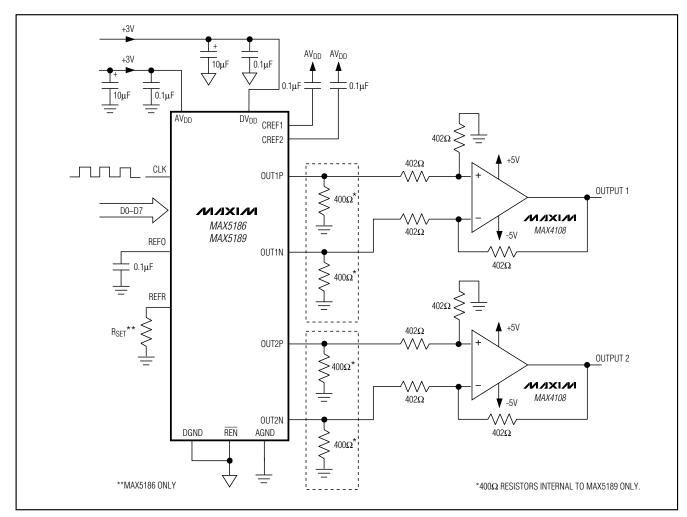


Figure 6. Differential to Single-Ended Conversion Using a Low-Distortion Amplifier

bypass CREF1 and CREF2 with low-ESR $0.1\mu F$ capacitors to AVDD.

The power-supply voltages should also be decoupled with large tantalum or electrolytic capacitors at the point they enter the PC board. Ferrite beads with additional decoupling capacitors forming a pi network can also improve performance.

_Chip Information

TRANSISTOR COUNT: 9464 SUBSTRATE CONNECTED TO AGND

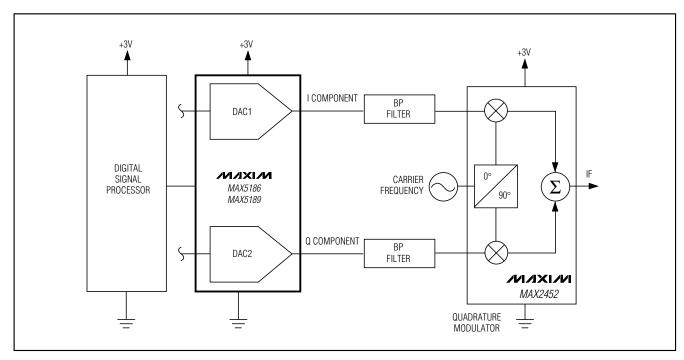
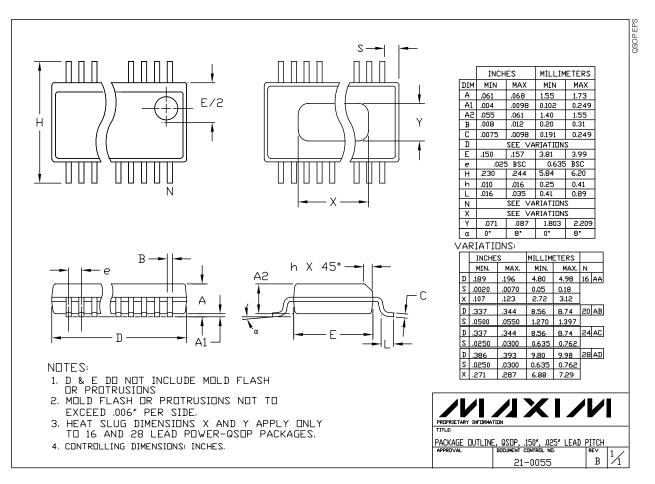


Figure 7. Using the MAX5186/MAX5189 for I/Q Signal Reconstruction

Package Information



Maxim cannot assume responsibility for use of any circuitry other than circuitry entirely embodied in a Maxim product. No circuit patent licenses are implied. Maxim reserves the right to change the circuitry and specifications without notice at any time.